

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/017,232 | | Applicant(s)/Patent Under Reexamination LACROIX, MICHAEL CHARLES | |
| | Examiner Patrick Miller | | Art Unit 2837 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-5,486,747 | 01-1996 | Welch, David W. | 318/811 |
| | B | US-6,157,160 | 12-2000 | Okawa et al. | 318/701 |
| | C | US-6,339,310 | 01-2002 | Sugiyama et al. | 318/783 |
| | D | US-6,208,107 | 03-2001 | Maske et al. | 318/685 |
| | E | US-6,140,793 | 10-2000 | Carr et al. | 318/696 |
| | F | US-4,804,894 | 02-1989 | Machida et al. | 388/812 |
| | G | US-6,008,611 | 12-1999 | Chen et al. | 318/599 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.